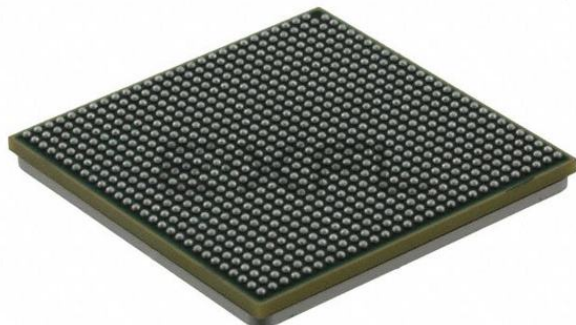




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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.0GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8547ecpxaqgd

- Dedicated single data rate SDRAM controller
- Parity support
- Default boot ROM chip select with configurable bus width (8, 16, or 32 bits)
- Four enhanced three-speed Ethernet controllers (eTSECs)
 - Three-speed support (10/100/1000 Mbps)
 - Four controllers designed to comply with IEEE Std. 802.3®, 802.3u, 802.3x, 802.3z, 802.3ac, and 802.3ab
 - Support for various Ethernet physical interfaces:
 - 1000 Mbps full-duplex IEEE 802.3 GMII, IEEE 802.3z TBI, RTBI, and RGMII
 - 10/100 Mbps full and half-duplex IEEE 802.3 MII, IEEE 802.3 RGMII, and RMII
 - Flexible configuration for multiple PHY interface configurations. See [Section 8.1, “Enhanced Three-Speed Ethernet Controller \(eTSEC\) \(10/100/1Gb Mbps\)—GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics,”](#) for more information.
 - TCP/IP acceleration and QoS features available
 - IP v4 and IP v6 header recognition on receive
 - IP v4 header checksum verification and generation
 - TCP and UDP checksum verification and generation
 - Per-packet configurable acceleration
 - Recognition of VLAN, stacked (queue in queue) VLAN, IEEE Std 802.2™, PPPoE session, MPLS stacks, and ESP/AH IP-security headers
 - Supported in all FIFO modes
 - Quality of service support:
 - Transmission from up to eight physical queues
 - Reception to up to eight physical queues
 - Full- and half-duplex Ethernet support (1000 Mbps supports only full duplex):
 - IEEE 802.3 full-duplex flow control (automatic PAUSE frame generation or software-programmed PAUSE frame generation and recognition)
 - Programmable maximum frame length supports jumbo frames (up to 9.6 Kbytes) and IEEE Std. 802.1™ virtual local area network (VLAN) tags and priority
 - VLAN insertion and deletion
 - Per-frame VLAN control word or default VLAN for each eTSEC
 - Extracted VLAN control word passed to software separately
 - Retransmission following a collision
 - CRC generation and verification of inbound/outbound frames
 - Programmable Ethernet preamble insertion and extraction of up to 7 bytes
 - MAC address recognition:
 - Exact match on primary and virtual 48-bit unicast addresses

Table 1. Absolute Maximum Ratings ¹ (continued)

Characteristic	Symbol	Max Value	Unit	Notes
Storage temperature range	T _{STG}	–55 to 150	°C	—

Notes:

- Functional and tested operating conditions are given in [Table 2](#). Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- The –0.3 to 2.75 V range is for DDR and –0.3 to 1.98 V range is for DDR2.
- The 3.63 V maximum is only supported when the port is configured in GMII, MII, RMII, or TBI modes; otherwise the 2.75 V maximum applies. See [Section 8.2, “FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications,”](#) for details on the recommended operating conditions per protocol.
- (M,L,O)V_{IN} may overshoot/undershoot to a voltage and for a maximum duration as shown in [Figure 2](#).

2.1.2 Recommended Operating Conditions

The following table provides the recommended operating conditions for this device. Note that the values in this table are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic		Symbol	Recommended Value	Unit	Notes
Core supply voltage		V _{DD}	1.1 V ± 55 mV	V	—
PLL supply voltage		AV _{DD}	1.1 V ± 55 mV	V	1
Core power supply for SerDes transceivers		SV _{DD}	1.1 V ± 55 mV	V	—
Pad power supply for SerDes transceivers		XV _{DD}	1.1 V ± 55 mV	V	—
DDR and DDR2 DRAM I/O voltage		GV _{DD}	2.5 V ± 125 mV 1.8 V ± 90 mV	V	—
Three-speed Ethernet I/O voltage		LV _{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	4
		TV _{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	—	4
PCI/PCI-X, DUART, system control and power management, I ² C, Ethernet MII management, and JTAG I/O voltage		OV _{DD}	3.3 V ± 165 mV	V	3
Local bus I/O voltage		BV _{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	—
Input voltage	DDR and DDR2 DRAM signals	MV _{IN}	GND to GV _{DD}	V	2
	DDR and DDR2 DRAM reference	MV _{REF}	GND to GV _{DD} /2	V	2
	Three-speed Ethernet signals	LV _{IN} TV _{IN}	GND to LV _{DD} GND to TV _{DD}	V	4
	Local bus signals	BV _{IN}	GND to BV _{DD}	V	—
	PCI, DUART, SYSCLK, system control and power management, I ² C, Ethernet MII management, and JTAG signals	OV _{IN}	GND to OV _{DD}	V	3

NOTE

From a system standpoint, if any of the I/O power supplies ramp prior to the V_{DD} core supply, the I/Os associated with that I/O supply may drive a logic one or zero during power-up, and extra current may be drawn by the device.

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface of the device.

7.1 DUART DC Electrical Characteristics

This table provides the DC electrical characteristics for the DUART interface.

Table 20. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	$OV_{DD} + 0.3$	V
Low-level input voltage	V_{IL}	-0.3	0.8	V
Input current ($V_{IN}^1 = 0$ V or $V_{IN} = V_{DD}$)	I_{IN}	—	± 5	μ A
High-level output voltage ($OV_{DD} = \min$, $I_{OH} = -2$ mA)	V_{OH}	2.4	—	V
Low-level output voltage ($OV_{DD} = \min$, $I_{OL} = 2$ mA)	V_{OL}	—	0.4	V

Note:

- Note that the symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

7.2 DUART AC Electrical Specifications

This table provides the AC timing parameters for the DUART interface.

Table 21. DUART AC Timing Specifications

Parameter	Value	Unit	Notes
Minimum baud rate	$f_{CCB}/1,048,576$	baud	1, 2
Maximum baud rate	$f_{CCB}/16$	baud	1, 2, 3
Oversample rate	16	—	1, 4

Notes:

- Guaranteed by design.
- f_{CCB} refers to the internal platform clock.
- Actual attainable baud rate is limited by the latency of interrupt processing.
- The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

8 Enhanced Three-Speed Ethernet (eTSEC)

This section provides the AC and DC electrical characteristics for the enhanced three-speed Ethernet controller. The electrical characteristics for MDIO and MDC are specified in [Section 9, “Ethernet Management Interface Electrical Characteristics.”](#)

8.1 Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1Gb Mbps)—GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics

The electrical characteristics specified here apply to all gigabit media independent interface (GMII), media independent interface (MII), ten-bit interface (TBI), reduced gigabit media independent interface (RGMII), reduced ten-bit interface (RTBI), and reduced media independent interface (RMII) signals except management data input/output (MDIO) and management data clock (MDC). The RGMII and RTBI interfaces are defined for 2.5 V, while the GMII, MII, and TBI interfaces can be operated at 3.3 or 2.5 V. The GMII, MII, or TBI interface timing is compliant with the IEEE 802.3. The RGMII and RTBI interfaces follow the *Reduced Gigabit Media-Independent Interface (RGMII) Specification Version 1.3* (12/10/2000). The RMII interface follows the *RMII Consortium RMII Specification Version 1.2* (3/20/1998). The electrical characteristics for MDIO and MDC are specified in [Section 9, “Ethernet Management Interface Electrical Characteristics.”](#)

8.1.1 eTSEC DC Electrical Characteristics

All GMII, MII, TBI, RGMII, RMII, and RTBI drivers and receivers comply with the DC parametric attributes specified in [Table 22](#) and [Table 23](#). The RGMII and RTBI signals are based on a 2.5-V CMOS interface voltage as defined by JEDEC EIA/JESD8-5.

Table 22. GMII, MII, RMII, and TBI DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Supply voltage 3.3 V	V_{DD} V_{DD}	3.13	3.47	V	1, 2
Output high voltage ($V_{DD}/V_{DD} = \min$, $I_{OH} = -4.0$ mA)	V_{OH}	2.40	$V_{DD}/V_{DD} + 0.3$	V	—
Output low voltage ($V_{DD}/V_{DD} = \min$, $I_{OL} = 4.0$ mA)	V_{OL}	GND	0.50	V	—
Input high voltage	V_{IH}	2.0	$V_{DD}/V_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	-0.3	0.90	V	—
Input high current ($V_{IN} = V_{DD}$, $V_{IN} = V_{DD}$)	I_{IH}	—	40	μ A	1, 2, 3
Input low current ($V_{IN} = \text{GND}$)	I_{IL}	-600	—	μ A	—

Notes:

1. V_{DD} supports eTSECs 1 and 2.
2. V_{DD} supports eTSECs 3 and 4.
3. The symbol V_{IN} , in this case, represents the V_{IH} and V_{IL} symbols referenced in [Table 1](#) and [Table 2](#).

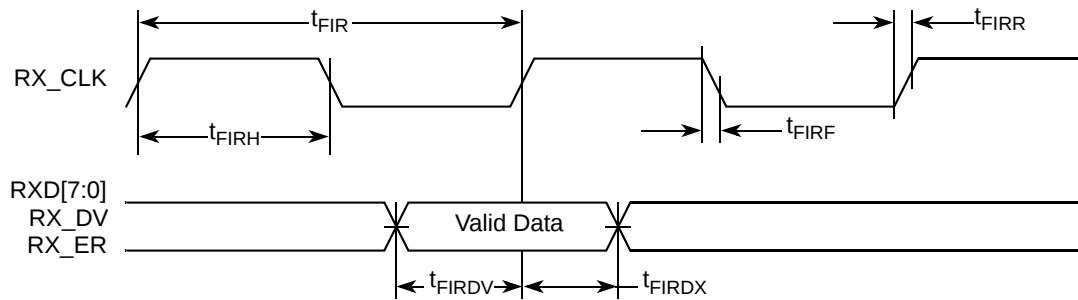


Figure 7. FIFO Receive AC Timing Diagram

8.2.2 GMII AC Timing Specifications

This section describes the GMII transmit and receive AC timing specifications.

8.2.2.1 GMII Transmit AC Timing Specifications

This table provides the GMII transmit AC timing specifications.

Table 26. GMII Transmit AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
GMII data TXD[7:0], TX_ER, TX_EN setup time	$t_{\text{GTKH}DV}$	2.5	—	—	ns
GTX_CLK to GMII data TXD[7:0], TX_ER, TX_EN delay	$t_{\text{GTKH}DX}$	0.5	—	5.0	ns
GTX_CLK data clock rise time (20%–80%)	$t_{\text{GT}XR}^2$	—	—	1.0	ns
GTX_CLK data clock fall time (80%–20%)	$t_{\text{GT}XF}^2$	—	—	1.0	ns

Notes:

- The symbols used for timing specifications follow the pattern $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{\text{GTKH}DV}$ symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) reaching the valid state (V) to state or setup time. Also, $t_{\text{GTKH}DX}$ symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) going invalid (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GTX} represents the GMII(G) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 8 shows the GMII transmit AC timing diagram.

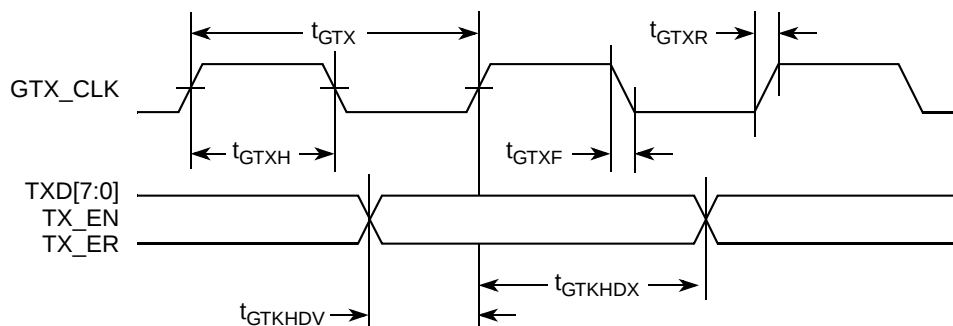


Figure 8. GMII Transmit AC Timing Diagram

8.2.2.2 GMII Receive AC Timing Specifications

This table provides the GMII receive AC timing specifications.

Table 27. GMII Receive AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period	t_{GRX}	—	8.0	—	ns
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	35	—	75	ns
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0	—	—	ns
RX_CLK clock rise (20%-80%)	t_{GRXR}^2	—	—	1.0	ns
RX_CLK clock fall time (80%-20%)	t_{GRXF}^2	—	—	1.0	ns

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 9 provides the AC test load for eTSEC.

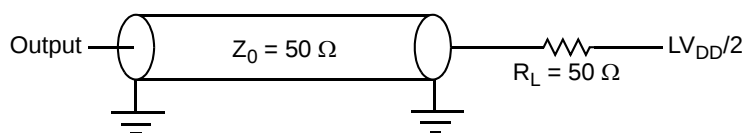


Figure 9. eTSEC AC Test Load

Table 42. Local Bus Timing Parameters—PLL Bypassed (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
LGTA/LUPWAIT input hold from local bus clock	$t_{LBIXKL2}$	-1.3	—	ns	4, 5
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKLOV1}$	—	-0.3	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKLOV2}$	—	-0.1	ns	4
Local bus clock to address valid for LAD	$t_{LBKLOV3}$	—	0	ns	4
Local bus clock to LALE assertion	$t_{LBKLOV4}$	—	0	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKLOX1}$	-3.7	—	ns	4
Output hold from local bus clock for LAD/LDP	$t_{LBKLOX2}$	-3.7	—	ns	4
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKLOZ1}$	—	0.2	ns	7
Local bus clock to output high impedance for LAD/LDP	$t_{LBKLOZ2}$	—	0.2	ns	7

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHGX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to local bus clock for PLL bypass mode. Timings may be negative with respect to the local bus clock because the actual launch and capture of signals is done with the internal launch/capture clock, which precedes LCLK by t_{LBKHK1} .
3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
4. All signals are measured from $BV_{DD}/2$ of the rising edge of local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
5. Input timings are measured at the pin.
6. The value of t_{LBOTOT} is the measurement of the minimum time between the negation of LALE and any change in LAD.
7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
8. Guaranteed by characterization.
9. Guaranteed by design.

13 I²C

This section describes the DC and AC electrical characteristics for the I²C interfaces of the device.

13.1 I²C DC Electrical Characteristics

This table provides the DC electrical characteristics for the I²C interfaces.

Table 45. I²C DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V _{IH}	0.7 × OV _{DD}	OV _{DD} + 0.3	V	—
Input low voltage level	V _{IL}	−0.3	0.3 × OV _{DD}	V	—
Low level output voltage	V _{OL}	0	0.2 × OV _{DD}	V	1
Pulse width of spikes which must be suppressed by the input filter	t _{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between 0.1 × OV _{DD} and 0.9 × OV _{DD} (max))	I _I	−10	10	μA	3
Capacitance for each I/O pin	C _I	—	10	pF	—

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. See the *MPC8548E PowerQUICC™ III Integrated Processor Family Reference Manual*, for information on the digital filter used.
3. I/O pins obstruct the SDA and SCL lines if OV_{DD} is switched off.

13.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I²C interfaces.

Table 46. I²C AC Electrical Specifications

Parameter	Symbol ¹	Min	Max	Unit	Notes
SCL clock frequency	f _{I2C}	0	400	kHz	—
Low period of the SCL clock	t _{I2CL}	1.3	—	μs	4
High period of the SCL clock	t _{I2CH}	0.6	—	μs	4
Setup time for a repeated START condition	t _{I2SVKH}	0.6	—	μs	4
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t _{I2SXKL}	0.6	—	μs	4
Data setup time	t _{I2DVKH}	100	—	ns	4
Data input hold time: CBUS compatible masters I ² C bus devices	t _{I2DXKL}	— 0	— —	μs	2
Data output delay time:	t _{I2OVKL}	—	0.9	—	3
Set-up time for STOP condition	t _{I2PVKH}	0.6	—	μs	—
Bus free time between a STOP and START condition	t _{I2KHDX}	1.3	—	μs	—

Table 54. PCI-X AC Timing Specifications at 133 MHz (continued)

Parameter	Symbol	Min	Max	Unit	Notes
$\overline{\text{HRESET}}$ to PCI-X initialization pattern hold time	t_{PCRHX}	0	50	ns	6, 12

Notes:

1. See the timing measurement conditions in the *PCI-X 1.0a Specification*.
2. Minimum times are measured at the package pin (not the test point). Maximum times are measured with the test point and load circuit.
3. Setup time for point-to-point signals applies to $\overline{\text{REQ}}$ and $\overline{\text{GNT}}$ only. All other signals are bused.
4. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
5. Setup time applies only when the device is not driving the pin. Devices cannot drive and receive signals at the same time.
6. Maximum value is also limited by delay to the first transaction (time for $\overline{\text{HRESET}}$ high to first configuration access, t_{PCRHFV}). The PCI-X initialization pattern control signals after the rising edge of $\overline{\text{HRESET}}$ must be negated no later than two clocks before the first $\overline{\text{FRAME}}$ and must be floated no later than one clock before $\overline{\text{FRAME}}$ is asserted.
7. A PCI-X device is permitted to have the minimum values shown for t_{PCKHOV} and t_{CYC} only in PCI-X mode. In conventional mode, the device must meet the requirements specified in PCI 2.2 for the appropriate clock frequency.
8. Device must meet this specification independent of how many outputs switch simultaneously.
9. The timing parameter t_{PCIVKH} is a minimum of 1.4 ns rather than the minimum of 1.2 ns in the *PCI-X 1.0a Specification*.
10. The timing parameter t_{PCRHFV} is a minimum of 10 clocks rather than the minimum of 5 clocks in the *PCI-X 1.0a Specification*.
11. Guaranteed by characterization.
12. Guaranteed by design.

transmitter that implements pre-emphasis (to equalize the link and reduce inter-symbol interference) need only comply with the transmitter output compliance mask when pre-emphasis is disabled or minimized.

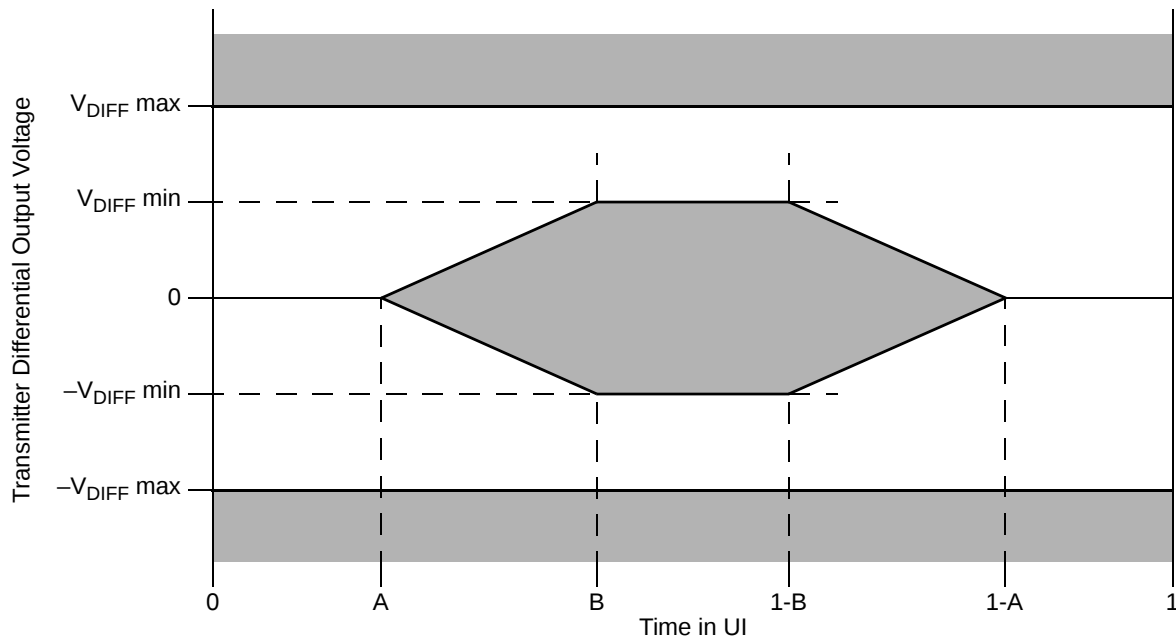


Figure 52. Transmitter Output Compliance Mask

Table 65. Transmitter Differential Output Eye Diagram Parameters

Transmitter Type	$V_{DIFFmin}$ (mV)	$V_{DIFFmax}$ (mV)	A (UI)	B (UI)
1.25 GBaud short range	250	500	0.175	0.39
1.25 GBaud long range	400	800	0.175	0.39
2.5 GBaud short range	250	500	0.175	0.39
2.5 GBaud long range	400	800	0.175	0.39
3.125 GBaud short range	250	500	0.175	0.39
3.125 GBaud long range	400	800	0.175	0.39

18.7 Receiver Specifications

LP-serial receiver electrical and timing specifications are stated in the text and tables of this section.

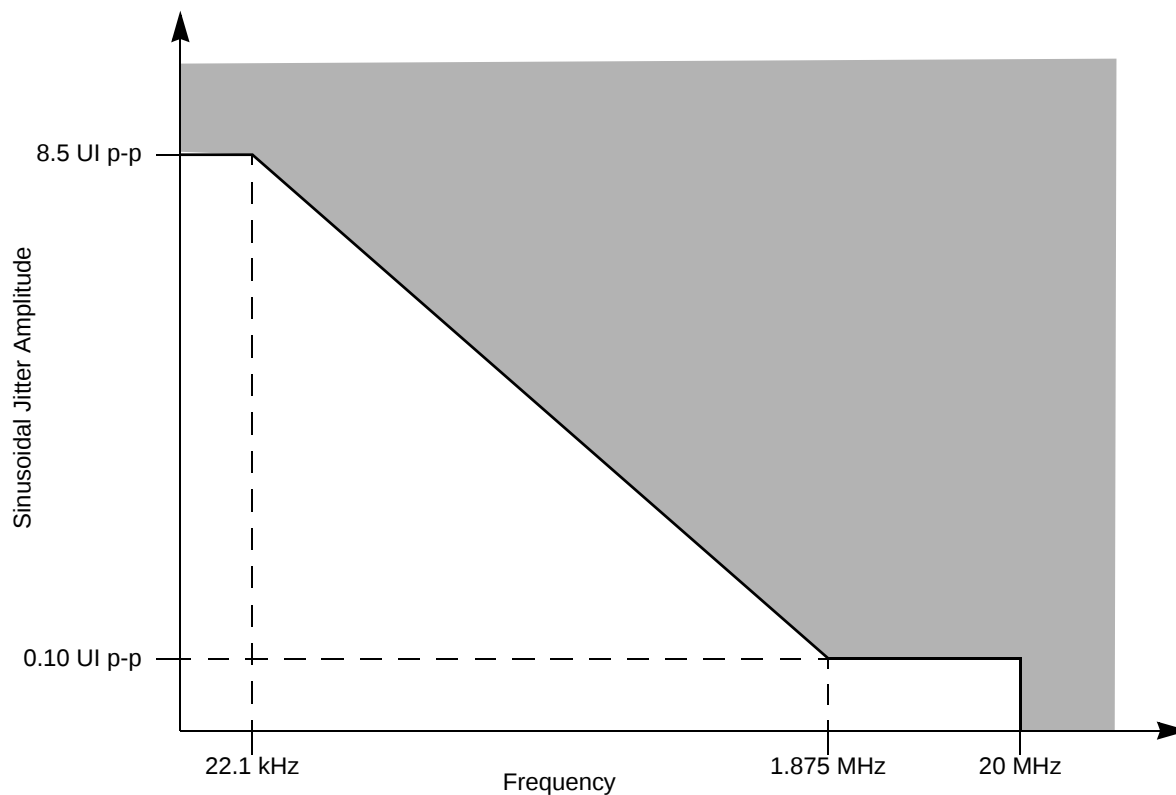
Receiver input impedance shall result in a differential return loss better than 10 dB and a common mode return loss better than 6 dB from 100 MHz to $(0.8) \times$ (baud frequency). This includes contributions from on-chip circuitry, the chip package, and any off-chip components related to the receiver. AC coupling

Table 68. Receiver AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential input voltage	V_{IN}	200	1600	mVp-p	Measured at receiver
Deterministic jitter tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined deterministic and random jitter tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total jitter tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple input skew	S_{MI}	—	22	ns	Skew at the receiver input between lanes of a multilane link
Bit error rate	BER	—	10^{-12}		—
Unit interval	UI	320	320	ps	± 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 53. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

**Figure 53. Single Frequency Sinusoidal Jitter Limits**

802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of IEEE Std. 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

18.9.1 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for template measurements is the continuous jitter test pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12} . The eye pattern shall be measured with AC coupling and the compliance template centered at 0 V differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100- Ω resistive $\pm$ 5% differential to 2.5 GHz.

18.9.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter test pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 V differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

18.9.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive $\pm$ 5% differential to 2.5 GHz.

18.9.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in [Section 18.7, “Receiver Specifications,”](#) and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in [Figure 54](#) and [Table 69](#). Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in [Section 18.7, “Receiver Specifications,”](#) is then added to the signal and the test load is replaced by the receiver being tested.

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Clock				
RTC	AF16	I	OV _{DD}	—
SYSCLK	AH17	I	OV _{DD}	—
JTAG				
TCK	AG28	I	OV _{DD}	—
TDI	AH28	I	OV _{DD}	12
TDO	AF28	O	OV _{DD}	—
TMS	AH27	I	OV _{DD}	12
TRST	AH23	I	OV _{DD}	12
DFT				
L1_TSTCLK	AC25	I	OV _{DD}	25
L2_TSTCLK	AE22	I	OV _{DD}	25
LSSD_MODE	AH20	I	OV _{DD}	25
TEST_SEL	AH14	I	OV _{DD}	25
Thermal Management				
THERM0	AG1	—	—	14
THERM1	AH1	—	—	14
Power Management				
ASLEEP	AH18	O	OV _{DD}	9, 19, 29
Power and Ground Signals				
GND	A11, B7, B24, C1, C3, C5, C12, C15, C26, D8, D11, D16, D20, D22, E1, E5, E9, E12, E15, E17, F4, F26, G12, G15, G18, G21, G24, H2, H6, H8, H28, J4, J12, J15, J17, J27, K7, K9, K11, K27, L3, L5, L12, L16, N11, N13, N15, N17, N19, P4, P9, P12, P14, P16, P18, R11, R13, R15, R17, R19, T4, T12, T14, T16, T18, U8, U11, U13, U15, U17, U19, V4, V12, V18, W6, W19, Y4, Y9, Y11, Y19, AA6, AA14, AA17, AA22, AA23, AB4, AC2, AC11, AC19, AC26, AD5, AD9, AD22, AE3, AE14, AF6, AF10, AF13, AG8, AG27, K28, L24, L26, N24, N27, P25, R28, T24, T26, U24, V25, W28, Y24, Y26, AA24, AA27, AB25, AC28, L21, L23, N22, P20, R23, T21, U22, V20, W23, Y21, U27	—	—	—
OV _{DD}	V16, W11, W14, Y18, AA13, AA21, AB11, AB17, AB24, AC4, AC9, AC21, AD6, AD13, AD17, AD19, AE10, AE8, AE24, AF4, AF12, AF22, AF27, AG26	Power for PCI and other standards (3.3 V)	OV _{DD}	—

Table 73. MPC8545E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI1_FRAME	AE11	I/O	OV _{DD}	2
PCI1_IDSEL	AG9	I	OV _{DD}	—
PCI1_REQ64/PCI2_FRAME	AF14	I/O	OV _{DD}	2, 5, 10
PCI1_ACK64/PCI2_DEVSEL	V15	I/O	OV _{DD}	2
PCI2_CLK	AE28	I	OV _{DD}	39
PCI2_IRDY	AD26	I/O	OV _{DD}	2
PCI2_PERR	AD25	I/O	OV _{DD}	2
PCI2_GNT[4:1]	AE26, AG24, AF25, AE25	O	OV _{DD}	5, 9, 35
PCI2_GNT0	AG25	I/O	OV _{DD}	—
PCI2_SERR	AD24	I/O	OV _{DD}	2,4
PCI2_STOP	AF24	I/O	OV _{DD}	2
PCI2_TRDY	AD27	I/O	OV _{DD}	2
PCI2_REQ[4:1]	AD28, AE27, W17, AF26	I	OV _{DD}	—
PCI2_REQ0	AH25	I/O	OV _{DD}	—
DDR SDRAM Memory Interface				
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV _{DD}	—
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV _{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	O	GV _{DD}	—
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV _{DD}	—
MDQS[0:8]	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV _{DD}	—
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	O	GV _{DD}	—
MBA[0:2]	F7, J7, M11	O	GV _{DD}	—
MWE	E7	O	GV _{DD}	—
MCAS	H7	O	GV _{DD}	—
MRAS	L8	O	GV _{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV _{DD}	11
MCS[0:3]	K8, J8, G8, F8	O	GV _{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV _{DD}	—
MCK[0:5]	J9, A15, G1, L9, B14, F2	O	GV _{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV _{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{PCI1_TRDY}}$	AG11	I/O	OV_{DD}	2
$\text{PCI1_REQ}[4:1]$	AH2, AG4, AG3, AH4	I	OV_{DD}	—
$\overline{\text{PCI1_REQ0}}$	AH3	I/O	OV_{DD}	—
PCI1_CLK	AH26	I	OV_{DD}	39
$\overline{\text{PCI1_DEVSEL}}$	AH11	I/O	OV_{DD}	2
$\overline{\text{PCI1_FRAME}}$	AE11	I/O	OV_{DD}	2
PCI1_IDSEL	AG9	I	OV_{DD}	—
cfg_pci1_width	AF14	I/O	OV_{DD}	112
Reserved	V15	—	—	110
Reserved	AE28	—	—	2
Reserved	AD26	—	—	110
Reserved	AD25	—	—	110
Reserved	AE26	—	—	110
cfg_pci1_clk	AG24	I	OV_{DD}	5
Reserved	AF25	—	—	101
Reserved	AE25	—	—	110
Reserved	AG25	—	—	110
Reserved	AD24	—	—	110
Reserved	AF24	—	—	110
Reserved	AD27	—	—	110
Reserved	AD28, AE27, W17, AF26	—	—	110
Reserved	AH25	—	—	110
DDR SDRAM Memory Interface				
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV_{DD}	—
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV_{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	O	GV_{DD}	—
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV_{DD}	—
$\overline{\text{MDQS}}[0:8]$	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV_{DD}	—
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	O	GV_{DD}	—
MBA[0:2]	F7, J7, M11	O	GV_{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
JTAG				
TCK	AG28	I	OV _{DD}	—
TDI	AH28	I	OV _{DD}	12
TDO	AF28	O	OV _{DD}	—
TMS	AH27	I	OV _{DD}	12
$\overline{\text{TRST}}$	AH23	I	OV _{DD}	12
DFT				
L1_TSTCLK	AC25	I	OV _{DD}	25
L2_TSTCLK	AE22	I	OV _{DD}	25
$\overline{\text{LSSD_MODE}}$	AH20	I	OV _{DD}	25
TEST_SEL	AH14	I	OV _{DD}	109
Thermal Management				
THERM0	AG1	—	—	14
THERM1	AH1	—	—	14
Power Management				
ASLEEP	AH18	O	OV _{DD}	9, 19, 29
Power and Ground Signals				
GND	A11, B7, B24, C1, C3, C5, C12, C15, C26, D8, D11, D16, D20, D22, E1, E5, E9, E12, E15, E17, F4, F26, G12, G15, G18, G21, G24, H2, H6, H8, H28, J4, J12, J15, J17, J27, K7, K9, K11, K27, L3, L5, L12, L16, N11, N13, N15, N17, N19, P4, P9, P12, P14, P16, P18, R11, R13, R15, R17, R19, T4, T12, T14, T16, T18, U8, U11, U13, U15, U17, U19, V4, V12, V18, W6, W19, Y4, Y9, Y11, Y19, AA6, AA14, AA17, AA22, AA23, AB4, AC2, AC11, AC19, AC26, AD5, AD9, AD22, AE3, AE14, AF6, AF10, AF13, AG8, AG27, K28, L24, L26, N24, N27, P25, R28, T24, T26, U24, V25, W28, Y24, Y26, AA24, AA27, AB25, AC28, L21, L23, N22, P20, R23, T21, U22, V20, W23, Y21, U27	—	—	—
OV _{DD}	V16, W11, W14, Y18, AA13, AA21, AB11, AB17, AB24, AC4, AC9, AC21, AD6, AD13, AD17, AD19, AE10, AE8, AE24, AF4, AF12, AF22, AF27, AG26	Power for PCI and other standards (3.3 V)	OV _{DD}	—
LV _{DD}	N8, R7, T9, U6	Power for TSEC1 and TSEC2 (2.5 V, 3.3 V)	LV _{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
TV _{DD}	W9, Y6	Power for TSEC3 and TSEC4 (2.5 V, 3.3 V)	TV _{DD}	—
GV _{DD}	B3, B11, C7, C9, C14, C17, D4, D6, D10, D15, E2, E8, E11, E18, F5, F12, F16, G3, G7, G9, G11, H5, H12, H15, H17, J10, K3, K12, K16, K18, L6, M4, M8, M13	Power for DDR1 and DDR2 DRAM I/O voltage (1.8 V, 2.5 V)	GV _{DD}	—
BV _{DD}	C21, C24, C27, E20, E25, G19, G23, H26, J20	Power for local bus (1.8 V, 2.5 V, 3.3 V)	BV _{DD}	—
V _{DD}	M19, N12, N14, N16, N18, P11, P13, P15, P17, P19, R12, R14, R16, R18, T11, T13, T15, T17, T19, U12, U14, U16, U18, V17, V19	Power for core (1.1 V)	V _{DD}	—
SV _{DD}	L25, L27, M24, N28, P24, P26, R24, R27, T25, V24, V26, W24, W27, Y25, AA28, AC27	Core power for SerDes transceivers (1.1 V)	SV _{DD}	—
XV _{DD}	L20, L22, N23, P21, R22, T20, U23, V21, W22, Y20	Pad power for SerDes transceivers (1.1 V)	XV _{DD}	—
AVDD_LBIU	J28	Power for local bus PLL (1.1 V)	—	26
AVDD_PCI1	AH21	Power for PCI1 PLL (1.1 V)	—	26
AVDD_PCI2	AH22	Power for PCI2 PLL (1.1 V)	—	26
AVDD_CORE	AH15	Power for e500 PLL (1.1 V)	—	26
AVDD_PLAT	AH19	Power for CCB PLL (1.1 V)	—	26
AVDD_SRDS	U25	Power for SRDSPLL (1.1 V)	—	26
SENSEVDD	M14	O	V _{DD}	13

20 Clocking

This section describes the PLL configuration of the device. Note that the platform clock is identical to the core complex bus (CCB) clock.

20.1 Clock Ranges

Table 75 through Table 77 provide the clocking specifications for the processor cores and Table 78, through Table 80 provide the clocking specifications for the memory bus.

Table 75. Processor Core Clocking Specifications (MPC8548E and MPC8547E)

Characteristic	Maximum Processor Core Frequency						Unit	Notes
	1000 MHz		1200 MHz		1333 MHz			
	Min	Max	Min	Max	Min	Max		
e500 core processor frequency	800	1000	800	1200	800	1333	MHz	1, 2

Notes:

1. **Caution:** The CCB to SYSClk ratio and e500 core to CCB ratio settings must be chosen such that the resulting SYSClk frequency, e500 (core) frequency, and CCB frequency do not exceed their respective maximum or minimum operating frequencies. See [Section 20.2, “CCB/SYSClk PLL Ratio,”](#) and [Section 20.3, “e500 Core PLL Ratio,”](#) for ratio settings.
- 2.)The minimum e500 core frequency is based on the minimum platform frequency of 333 MHz.

Table 76. Processor Core Clocking Specifications (MPC8545E)

Characteristic	Maximum Processor Core Frequency						Unit	Notes
	800 MHz		1000 MHz		1200 MHz			
	Min	Max	Min	Max	Min	Max		
e500 core processor frequency	800	800	800	1000	800	1200	MHz	1, 2

Notes:

1. **Caution:** The CCB to SYSClk ratio and e500 core to CCB ratio settings must be chosen such that the resulting SYSClk frequency, e500 (core) frequency, and CCB frequency do not exceed their respective maximum or minimum operating frequencies. See [Section 20.2, “CCB/SYSClk PLL Ratio,”](#) and [Section 20.3, “e500 Core PLL Ratio,”](#) for ratio settings.
- 2.)The minimum e500 core frequency is based on the minimum platform frequency of 333 MHz.

Table 88. Document Revision History (continued)

Rev. Number	Date	Substantive Change(s)
2	04/2008	- Removed 1:1 support on Table 82, “e500 Core to CCB Clock Ratio.” - Removed MDM from Table 18, “DDR SDRAM Input AC Timing Specifications.” MDM is an Output. Figure 57, “PLL Power Supply Filter Circuit with PLAT Pins” (AVDD_PLAT). Figure 58, “PLL Power Supply Filter Circuit with CORE Pins” (AVDD_CORE). - Split Figure 59, “PLL Power Supply Filter Circuit with PCI/LBIU Pins,” (formerly called just “PLL Power Supply Filter Circuit”) into three figures: the original (now specific for AVDD_PCI/AVDD_LBIU) and two new ones.
1	10/2007	- Adjusted maximum SYSCLK frequency down in Table 5, “SYSCLK AC Timing Specifications” per device erratum GEN-13. - Clarified notes to Table 6, “EC_GTX_CLK125 AC Timing Specifications.” - Added Section 4.4, “PCI/PCI-X Reference Clock Timing.” - Clarified descriptions and added PCI/PCI-X to Table 9, “PLL Lock Times.” - Removed support for 266 and 200 Mbps data rates per device erratum GEN-13 in Section 6, “DDR and DDR2 SDRAM.” - Clarified Note 4 of Table 19, “DDR SDRAM Output AC Timing Specifications.” - Clarified the reference clock used in Section 7.2, “DUART AC Electrical Specifications.” - Corrected $V_{IH}(\text{min})$ in Table 22, “GMII, MII, RMII, and TBI DC Electrical Characteristics.” - Corrected $V_{IL}(\text{max})$ in Table 23, “GMII, MII, RMII, TBI, RGMII, RTBI, and FIFO DC Electrical Characteristics.” - Removed DC parameters from Table 24, Table 25, Table 26, Table 27, Table 28, Table 29, Table 32, Table 34, and Table 35. - Corrected $V_{IH}(\text{min})$ in Table 36, “MII Management DC Electrical Characteristics.” - Corrected $t_{MDC}(\text{min})$ in Table 37, “MII Management AC Timing Specifications.” - Updated parameter descriptions for $t_{LBIVKH1}$, $t_{LBIVKH2}$, $t_{LBIXKH1}$, and $t_{LBIXKH2}$ in Table 40, “Local Bus Timing Parameters (BV_{DD} = 3.3 V)—PLL Enabled” and Table 40, “Local Bus Timing Parameters (BV_{DD} = 2.5 V)—PLL Enabled.” - Updated parameter descriptions for $t_{LBIVKH1}$, $t_{LBIVKL2}$, $t_{LBIXKH1}$, and $t_{LBIXKL2}$ in Table 42, “Local Bus Timing Parameters—PLL Bypassed.” Note that $t_{LBIVKL2}$ and $t_{LBIXKL2}$ were previously labeled $t_{LBIVKH2}$ and $t_{LBIXKH2}$. - Added LUPWAIT signal to Figure 23, “Local Bus Signals (PLL Enabled)” and Figure 24, “Local Bus Signals (PLL Bypass Mode).” - Added LGTA signal to Figure 25, Figure 26, Figure 27 and Figure 28. - Corrected LUPWAIT assertion in Figure 26 and Figure 28. - Clarified the PCI reference clock in Section 15.2, “PCI/PCI-X AC Electrical Specifications” - Added Section 17.1, “Package Parameters.” - Added PBGA thermal information in Section 21.2, “Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid.” - Updated.” - Updated Table 87, “Part Numbering Nomenclature.”
0	07/2007	Initial Release